



**European Virtual IBIS Summit with Virtual SPI 2021**  
**May 12, 2021**

# Frequency-Dependent Per-Port Renormalization

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# Agenda

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- ❖ Problem statement
- ❖ Study summary
- ❖ Introduction to the FDPP method
- ❖ Case study of applying FDPP
- ❖ Comparison of the results obtained by the conventional method and the FDPP method

# Problem statement

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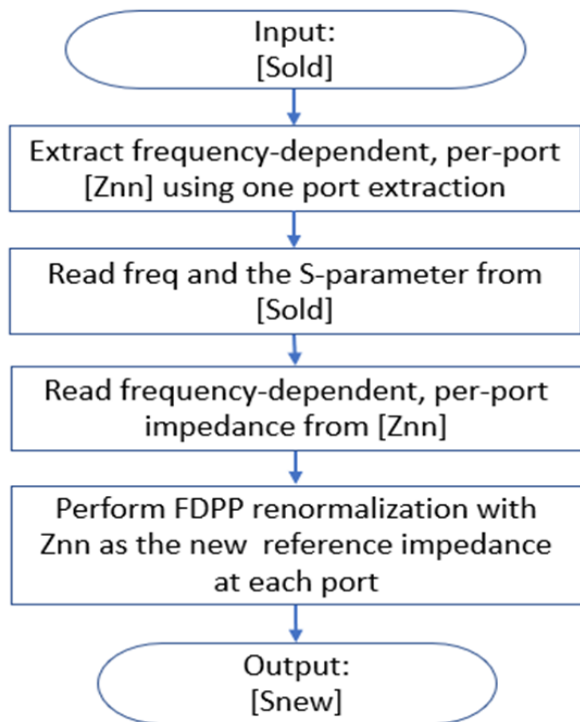
- Conventionally, the industry uses fixed impedance values as the TX/RX terminations
- In reality the TX/RX termination impedances vary with frequency (frequency-dependent) rather than be a constant value throughout the frequency range
- In addition, the TX and RX terminations have different characteristics from each other
- Should we use FDPP (Frequencydependent Per-port Renormalization) impedance instead of constant impedance? Is it worthwhile to make such change?

# Study summary

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- Compared to the conventional method, the S-param obtained by the FDPP method show remarkably worse return loss, and less worse insertion loss
- The eye/COM obtained by the FDPP method also show worse results compared to the conventional method. The degradation can be as large as ~10%
- **Recommend to use FDPP for end2end channel S-param extraction**
- In addition, one proposal to Touchstone spec:
  - Add support to frequency-dependent impedance

# Computation flow of FDPP



Sold: The original S-param extracted using fixed impedance.  
Snew: The renormalized S-param using FDPP method

$$[S'] = [A]^{-1} \cdot ([S] - [R]) \cdot ([I] - [R] \cdot [S])^{-1} \cdot [A] \quad (3)$$

Where,

R is the reflection matrix,

$$[R] = \begin{bmatrix} r(Z_1) & 0 & \cdots & 0 \\ 0 & r(Z_2) & \cdots & 0 \\ \vdots & \vdots & \ddots & \vdots \\ 0 & 0 & \cdots & r(Z_n) \end{bmatrix},$$

$r(Z_n)$  is the reflection coefficient of each port,

$$r(Z_n) = \frac{Z_n - Z_{n, \text{before}}}{Z_n + Z_{n, \text{before}}}$$

[A] is the conversion matrix,

$$[A] = \begin{bmatrix} A_1 & 0 & \cdots & 0 \\ 0 & A_2 & \cdots & 0 \\ \vdots & \vdots & \ddots & \vdots \\ 0 & 0 & \cdots & A_n \end{bmatrix},$$

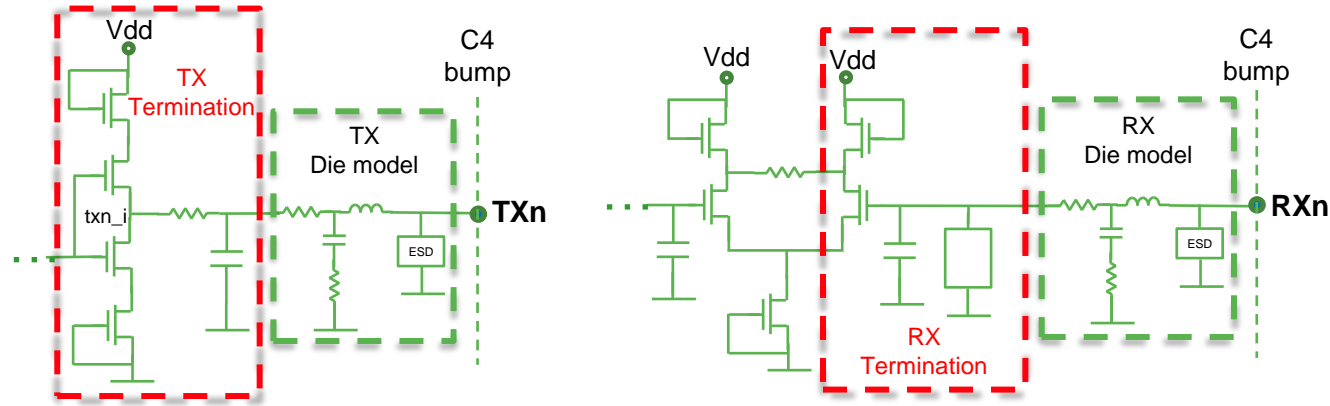
$[A_n]$  is the conversion coefficient for each port,

$$A_n = \sqrt{\frac{Z_n}{Z_{n, \text{before}}}} \cdot \frac{1}{Z_n + Z_{n, \text{before}}}$$

I is identity matrix.

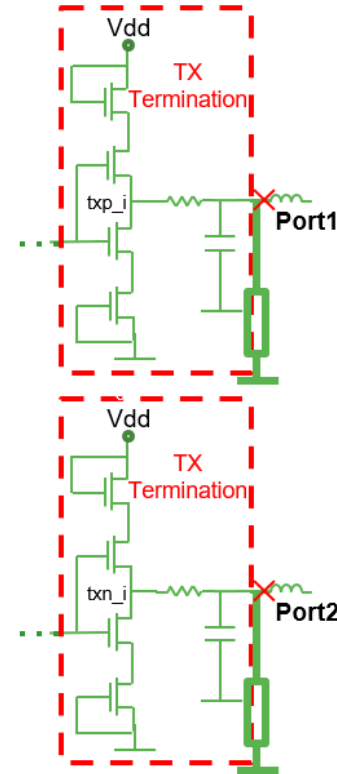
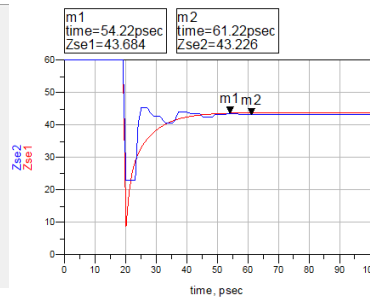
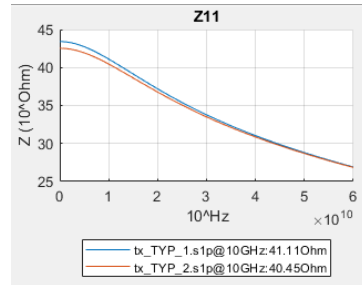
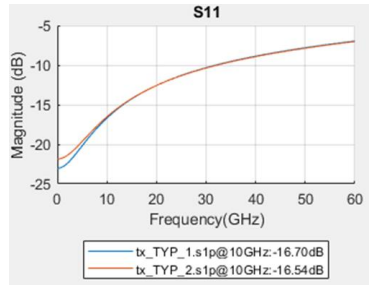
# TX/RX Termination + die model

- TX Termination: series termination targeted at 42.5Ohm
- RX Termination: shunt termination targeted at 42.5Ohm
- With calibration circuit the termination of TX/RX can be tuned pretty close to 42.5Ohm, but only around the Nyquist rather than across the full frequency range



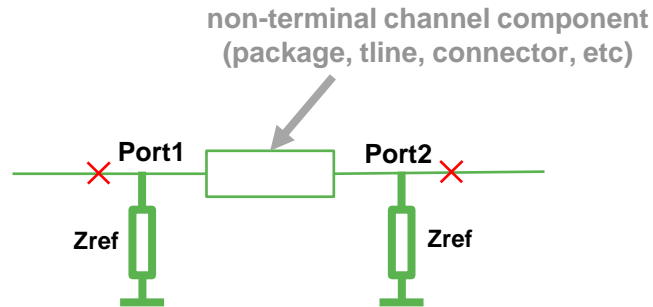
# One-port termination extraction

- The TX/RX Termination should be extracted using One-port termination extraction technique
- Quite often, designers don't really do this extraction – they simply use the calibration target impedance (42.5 Ohm, 50 Ohm, etc.) in channel simulation
- Due to the existence of parasitics, it is impossible to have a constant impedance across the frequency range which is evidenced by the plots below – neither S11 nor Z11 is constant over the frequency range
- Frequency-dependent termination impedance should be used rather than constant impedance!



# Case#1: Extracting the snp of non-terminal channel components

- The **Non-terminal** channel components
  - All channel components that are not the TX/RX terminations, e.g., die, package, channel, connector, etc.
- Proposed extraction method for Non-terminal channel components
  - Using fixed Zref, eg, 42.5Ohm, 50Ohm, or else value, for the extraction of the S-params of each non-terminal component. The impedances used can be different from each other
- The reasons for not using FDPP impedance to extract non-terminal channel components:
  - There is no need to use FDPP in cascading. Fixed impedance gives the identical result as FDPP (if ever feasible)
  - So far the Touchstone 2.0 can only support per-port impedance, but not frequency-dependent impedance. This limitation makes it impossible to implement FDPP S-params in TS format. To that goal proprietary S-param format has to be used

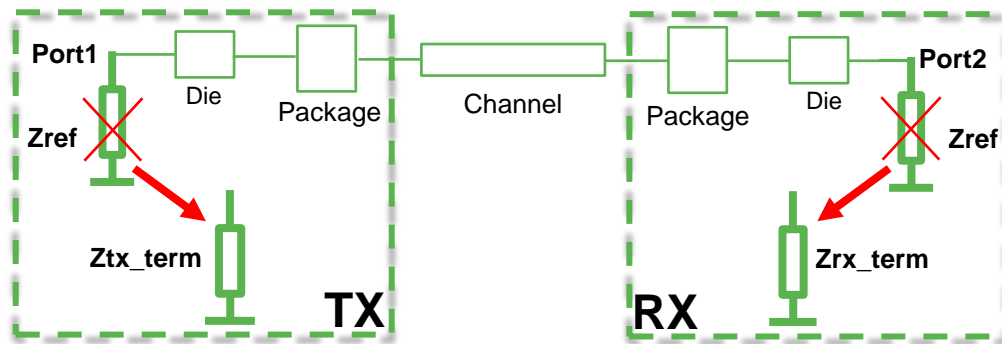


Non-terminal channel component model extraction



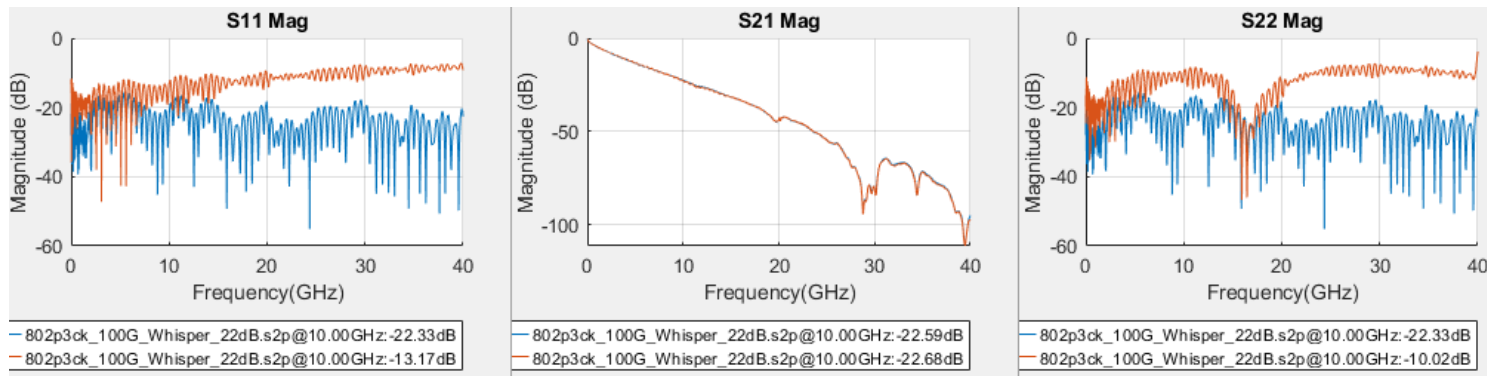
# Case#2: Extracting end2end channel model

- For **end2end** channel model extraction, recommend to replace the fixed  $Z_{ref}$  by frequency-dependent  $Z_{tx\_term}$  and  $Z_{rx\_term}$  for better accuracy
  - Renormalize all non-terminal channel components' models to one uniform impedance and cascade them into one S-param
  - Apply FDPP TX/RX terminations to the cascaded S-param to obtain a full channel S-param which better reflects the characteristics of the channel than using fixed impedance
  - Apply the FDPP-extracted/renormalized end2end channel S-param in eye/COM simulation to obtain accurate channel performance evaluation



# Channel example#1: S-param

- Large deviations are shown on the return loss items (S11, S22) extracted using fixed Zref vs using FDPP Zref
- The S11, S22 extracted by FDPP method is remarkably worse than that extracted using fixed Zref
- S21 does not deviate too much between using the two methods (-22.59dB vs -22.68dB, at 10GHz)



Blue: Zref = 42.5Ohm;

Red: Zref = frequency-dependent Ztx\_term, Zrx\_term

# Channel example#1: eye, COM

- Both the eye results and the COM FOM obtained by FDPP method are worse than that obtained using fixed impedance 42.5Ohm (which is the target impedance for this serdes TX/RX designs)
- The COM performance deviation is -9.77% which is quite beyond the negligible range. For better accuracy, the fixed Zref should be replaced by frequency-dependent Ztx\_term and Zrx\_term, in a per-port manner

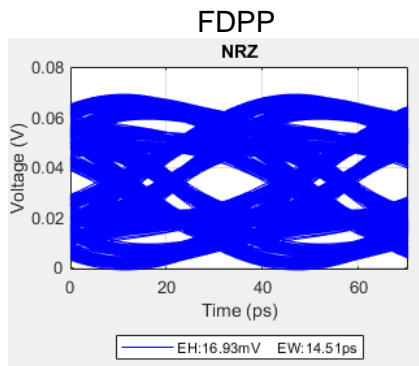
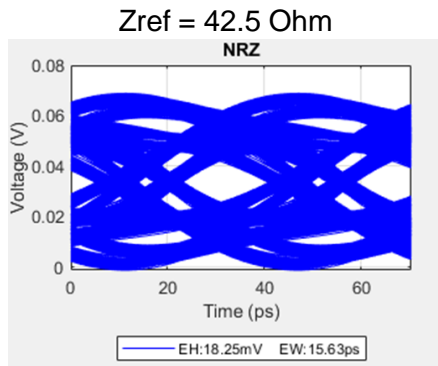
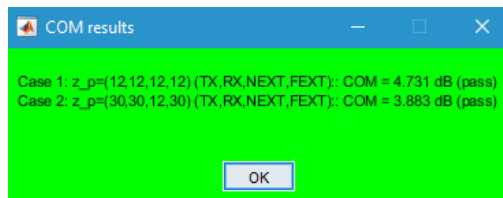
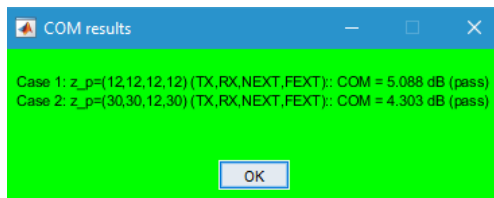


Table I: EH/EW & COM values

| Termination | EH (mV) | EW (ps) | COM (dB) |
|-------------|---------|---------|----------|
| Constant    | 18.25   | 16.93   | 4.30     |
| FDPP        | 15.69   | 14.51   | 3.88     |
| Delta       | -7.23%  | -7.2%   | -9.77%   |



# Thank You

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